



NSAI
Standards

Irish Standard
I.S. EN 60749-44:2016

Semiconductor devices - Mechanical and climatic test methods - Part 44: Neutron beam irradiated single event effect (SEE) test method for semiconductor devices

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I.S. EN 60749-44:2016

Incorporating amendments/corrigenda/National Annexes issued since publication:

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I.S. xxx: Irish Standard — national specification based on the consensus of an expert panel and subject to public consultation.

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Údarás um Chaighdeáin Náisiúnta na hÉireann

National Foreword

I.S. EN 60749-44:2016 is the adopted Irish version of the European Document EN 60749-44:2016, Semiconductor devices - Mechanical and climatic test methods - Part 44: Neutron beam irradiated single event effect (SEE) test method for semiconductor devices

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ICS 31.080.01

English Version

Semiconductor devices - Mechanical and climatic test methods -
Part 44: Neutron beam irradiated single event effect (SEE) test
method for semiconductor devices
(IEC 60749-44:2016)

Dispositifs à semiconducteurs - Méthodes d'essais
mécaniques et climatiques - Partie 44: Méthode d'essai des
effets d'un événement isolé (SEE) irradié par un faisceau
de neutrons pour des dispositifs à semiconducteurs
(IEC 60749-44:2016)

Halbleiterbauelemente - Mechanische und klimatische
Prüfverfahren - Teil 44: Prüfverfahren zur Einzelereignis-
Effekt-Neutronenbestrahlung von Halbleiterbauelementen
(IEC 60749-44:2016)

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This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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EN 60749-44:2016

European foreword

The text of document 47/2303/FDIS, future edition 1 of IEC 60749-44, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60749-44:2016.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-05-25
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2019-08-25

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The text of the International Standard EC 60749-44:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated :

IEC 60749-38 NOTE Harmonized as EN 60749-38.

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